Application/Control No. Applicant(s)/Patent Under Reexamination 10/790,111 TANAKA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 LEE D. WILSON 3723 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY * 65/30.14 US-6,782,717 B2 08-2004 Saito et al. Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-J Κ US-US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s τ **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

W

Х